

Specification MOS/CV4040 Issue 2 Dated 6.11.56 To be read in conjunction with K1001, BS448 and BS1409	<u>SECURITY</u>	
	<u>Specification</u> UNCLASSIFIED	<u>Valve</u> UNCLASSIFIED

Indicates a change ←

TYPE OF VALVE - Reliable Pulse Tetrode CATHODE - Indirectly-heated ENVELOPE - Glass PROTOTYPE - CV416	<u>MARKING</u> See K1001/4																	
	<u>BASE</u> See BS448/B7G/1.1																	
<u>CONNECTIONS</u>																		
<table border="1"> <thead> <tr> <th>Pin</th> <th>Electrode</th> </tr> </thead> <tbody> <tr> <td>1</td> <td>Control Grid g1</td> </tr> <tr> <td>2</td> <td>Cathode k</td> </tr> <tr> <td>3</td> <td>Heater h</td> </tr> <tr> <td>4</td> <td>Heater h</td> </tr> <tr> <td>5</td> <td>Anode a</td> </tr> <tr> <td>6</td> <td>Beam Plates bp</td> </tr> <tr> <td>7</td> <td>Screen Grid g2</td> </tr> </tbody> </table>		Pin	Electrode	1	Control Grid g1	2	Cathode k	3	Heater h	4	Heater h	5	Anode a	6	Beam Plates bp	7	Screen Grid g2	
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<u>DIMENSIONS</u> See BS448/B7G/2.1																		
<u>Size Ref. No. 2</u>																		
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<u>MOUNTING POSITION</u> Any																		
<u>NOTES</u>																		
<p>A. Tested at $V_a = V_{g2} = 250V$; $V_{g1} = -6.25V$ ($I_a = 64mA$ approx. tested under pulsed conditions).</p> <p>B. <u>Caution to Electronic Equipment Design Engineers:</u> Special attention should be given to the temperature of valves to be operated in aircraft. Reliability will be seriously impaired if the maximum bulb temperature is exceeded. The life expectancy may be reduced if conditions other than those specified for life test are imposed on the valve and will be reduced appreciably if absolute maximum ratings are exceeded. Both reliability and performance will be jeopardised if heater voltage ratings are exceeded; life and reliability performance are directly related to the degree that regulation of the heater voltage is maintained at its centre-rated value.</p>																		

CV4040/2/1

Z.14234.R.

To be performed in addition to those applicable in K1001
and in the specified order unless otherwise agreed with the Inspecting Authority.

Test Conditions - unless otherwise specified											
		Vh (V)	Va (V)	Vg2 (V)	Ia (mA)						
K1001	Test	Test Conditions		AQL %	Insp Level	Sym bol	Limits				
							Min	LAL	Bogey	UAL	
7.1	Glass Strain	No voltages	6.5	I			-	-	-	-	
5.2	<u>GROUP A</u> Insulation Reverse Grid Current	Vg1 - all = -100V Vg2 - all = -300V Va - all = -300V Rgl = 500k Max	100%	R	100 100 100	- - -	- - -	- - -	- - -	M \sim M \sim M \sim	
	<u>GROUP B</u> Heater Current Heater-cathode Leakage Current Negative Grid Voltage Negative Grid Voltage for cut-off Screen Current Mutual Conductance	Combined AQL Vhk = \pm 100V Ia = 100mA	1.0 0.65 0.65 0.65 0.65 0.65	II II V2 II V2 II	Ih Ihk V2 Vg1 Vg1 Ig2 gm	0.27 - - 8.4 - - 2.05 2.6	- - - - - 12.5 3.1	0.30 - - - - 37 3.6	- - - - - 15.8 4.0	0.33 10 - 38 5.1 5.0 - 1.1	A uA uA V V mA mA/V mA/V
	<u>GROUP C</u> Change in Vg2 Pulse Anode Current Vibration Noise Output	Combined AQL Vg1 reduced by 2V, Vg2 reduced to maintain Ia = 17mA Va = Vg2 = 300V Vg1 = -100V Pulse amp = +100V tp = 10 to 15 usecs Duty cycle = 0.25 Va(b) = 250V Vg1 = -17V RL = 2k	6.5 2.5 2.5	I I I	Δ Vg2 Ia (pk)	15 1.33 -	- - -	- - -	- - -	25 - -	V mA mV (pk-pk)
7.2	<u>GROUP D</u> Grid Emission Capacitance Base Strain	Vh = 7.0V Vg1 = -38V Rgl = 500K Measured on a 1 Mc/s bridge with the valve mounted in a fully screened socket. Shielded No voltages	6.5 6.5 6.5	IA IC IA	Igl C out C in Ca gl	- 4.4 5.2 -	- - - 0.03	- 5.2 6.2 -	- - - -	-1.5 6.1 7.1 .05	uA pF pF pF
11.2	<u>GROUP E</u> Resonance Search Vibration Noise Output Resonant Frequency	Va(b) = 250V Vg1 = -17V RL = 2k Frequency range 25-500 c/s	2.5	IC	Va AC f	- 200	- -	- -	- -	Record Record	mV (pk-pk) c/s

K1001	Test	Test Conditions	AQL %	Insp. Level	Symbol	Limits					Units	
						Min.	LAL	Bogey	UAL	Max.		
11.3	Fatigue	Vh = 6.9V switched 1 min on, 3 mins off Va = Vg2 = 0 Frequency = 170 c/s Min pk accel = 5g Duration = 30, 39, 30 hrs.		IA								
	<u>Post Fatigue Tests</u>											
	Vibration Noise Output	Va(b) = 250V Vgl = -17V RL = 2k	2.5	Va AC	-	-	-	-	100	mV (pk-pk)	↔	
	Heater-cathode Leakage Current	Vhk = ± 100V	2.5	Ihk	-	-	-	-	30	uA		
	Reverse Grid Current	Rgl = 500k Max.	2.5	Igl	-	-	-	-	1.5	uA		
	Mutual Conductance		2.5	gm	2.5	-	-	-	5.0	mA/V		
11.4	Shock	No voltages Hammer angle = 30°		IA								
	<u>Post Shock Tests</u>											
	Vibration Noise Output	Va(b) = 250V Vgl = -17V RL = 2k	2.5	Va AC	-	-	-	-	100	mV (pk-pk)		
	Heater-cathode Leakage current	Vhk = ± 100V	2.5	Ihk	-	-	-	-	30	uA		
	Reverse Grid Current	Rgl = 500k Max.	2.5	Igl	-	-	-	-	1.5	uA		
	Mutual Conductance		2.5	gm	2.5	-	-	-	5.0	mA/V		
	<u>GROUP F</u>											
AVI/5	Life	Va=250V; Vg2=200V; Vhk=100V; Rgl=500k; Rk=1000										
AVI/ 5.1	<u>Stability Life Test</u>											
	Change in Pulse Anode Current	Note 1	1.0	I	ΔIa (pk)	-	-	-	-	20	%	↔
AVI/ 5.3	Intermittent Life Test											
AVI/ 5.6	<u>Life Test End-point</u> (500 hrs)		6.5	IA								
	Inoperatives		2.5									
	Heater Current		2.5	Ih	0.27	-	-	-	0.33	A		
	Heater-cathode Leakage Current	Vhk = ± 100V	2.5	Ihk	-	-	-	-	10	uA		
	Reverse Grid Current	Rgl = 500k Max.	2.5	Igl	-	-	-	-	1.0	uA		
	Pulse Anode Current	Note 1	2.5	Ia(pk)	100	-	-	-	-	mA		
	do Average change			ΔIa(pk)	-	-	-	-	25	%		
	Negative Grid Voltage		4.0	Vgl	7.4	-	-	-	15.8	V		
	Insulation		4.0	R	50	-	-	-	-	M ↗		
					50	-	-	-	-	M ↘		
					50	-	-	-	-	M ↘		
					50	-	-	-	-	M ↗		

K1COL	Test	Test Conditions	AQL %	Insp. Level	Sym- bol	Limits					Units
						Min.	LAL	Bogey	UAL	Max.	
GROUP F											
A VI	<u>Life Test End-point</u> (1000 hrs.)		10.0	IA						0.33	A
	Inoperatives		4.0								
	Heater Current		4.0		Ih	0.27	-	-	-	10	uA
	Leakage Current	Vhk = ± 100V	4.0		Ihk	-	-	-	-	1.5	uA
	Reverse Grid Current	Rgl = 500k Max.	4.0		Igl	-	-	-	-	-	mA
	Pulse Anode Current	Note 1	4.0		Ia(pk)	90	-	-	-	-	
	Negative Grid Voltage		6.5		Vgl	6.6	-	-	-	15.8	V
GROUP G											
A IX				100%							
/2.5	Electrical re-test after										
AVI	28-day holding period										
/5.6	Inoperatives										
	Reverse Grid Current	Rgl = 500k Max	0.5		Igl	-	-	-	-	1.0	uA

NOTE

1. The test conditions specified for Pulse Anode Current in Group C shall apply.